查询CD4078B供应商

捷多邦,专业PCB打样工厂,24小时加急出货

EXAS ISTRUMENTS

CMOS 8-Input NOR/OR Gate

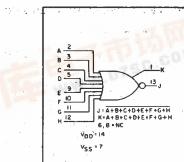
High-Voltage Types (20-Volt Rating)

CD4078B NOR/OR Gate provides the system designer with direct implementation of the positive-logic 8-input NOR and OR functions and supplements the existing family of CMOS gates.

The CD4078B types are supplied in 14-lead dual-in-line ceramic packages (D and F suffixes), 14-lead dual-in-line plastic packages (E suffix), and in chip form (H suffix).

Features:

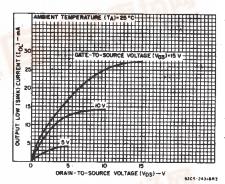
- Medium-Speed Operation: tPHL, tPLH = 75 ns (typ.) at VDD = 10 V
- **Buffered** inputs and output
- 5-V, 10-V, and 15-V parametric ratings
- Standardized symmetrical output characteristics
- 100% tested for quiescent current at 20 V Maximum input current of 1 µA at 18 V over full package-temperature range: 100 nA at 18 V and 25°C
- Noise margin (over full package-temperature range): 1 V at VDD = 5 V
- 2 V at VDD = 10 V 2.5 V at VDD = 15 V
- Meets all requirements of JEDEC Tentative Standard No. 13B, "Standard Specifications for Description of 'B' Series CMOS Devices"

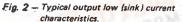


CD4078B Types

9205 - 2387 784



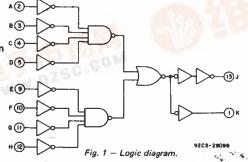




RECOMMENDED **OPERATING CONDITIONS** For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

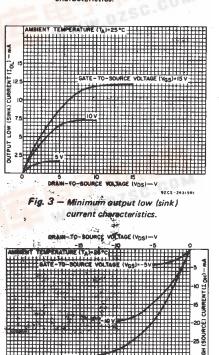
CHARACTERISTIC	Min.	Max.	Units
Supply-Voltage Range (For T _A Full Package			
Temperature Range)	3	18	V

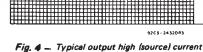
df.dzsc.com



DYNAMIC ELECTRICAL CHARACTERISTICS At $T_A = 25^{\circ}C$; Input t_r , $t_f = 20 \text{ ns}$, $C_L = 50 \text{ pF}$, $R_L = 200 k\Omega$

CHARACTERISTIC	TEST CONDI	COLIN			
CHANACIENISTIC	WWW	V _{DD} VOLTS	TYP.	MAX.	
Propagation Delay Time,		5	150	300	14
tPHL, tPLH		10	75	150	ns
		15	55	110	
Transition Time,		5	100	200	1
		10	50	100	ns
		15	40	80	
Input Capacitance, CIN	Any Input		5	7.5	pF





characteristics.

Ē

DC SUPPLY-VOLTAGE RANGE, (VDD) Voltages referenced to VSS Terminal)

MAXIMUM RATINGS, Absolute-Maximum Values:

POWER DISSIPATION PER PACKAGE (PD):	
For T _A = -55°C to +100°C	
For $T_A = +100^{\circ}C$ to $+125^{\circ}C$	Derate Linearity at 12mW/°C to 200mW
DEVICE DISSIPATION PER OUTPUT TRANSISTOR	
FOR T _A = FULL PACKAGE-TEMPERATURE RANGE (All Package	Types)
OPERATING-TEMPERATURE RANGE (TA)	
STORAGE TEMPERATURE RANGE (Tstg)	
LEAD TEMPERATURE (DURING SOLDERING):	• • • • • • • • • • • • • • • • • • •

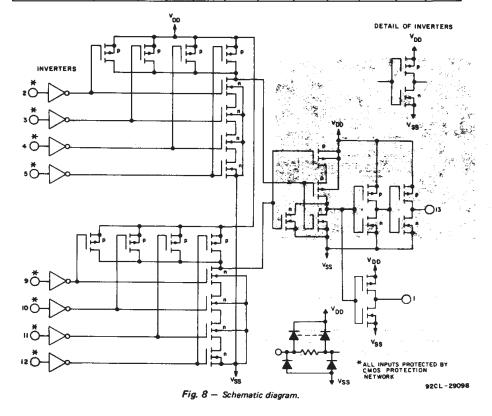
At distance 1/16 ± 1/32 inch (1.59 ± 0.79mm) from case for 10s max+265°C

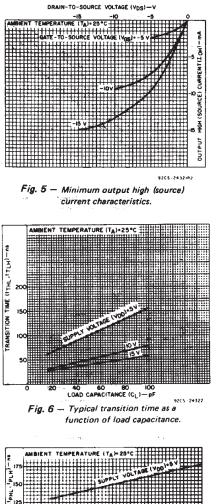
Data sheet acquired from Harris Semiconductor SCHS059

CD4078B Types

STATIC ELECTRICAL CHARACTERISTICS

CHARACTER	CONDITIONS			LIMITS AT INDICATED TEMPERATURES (°C)						UNITS	
ISTIC	٧o	VIN	VDD					+25			
	(V)	(V)	(V)	55	-40	+85	+125	Min.	" Тур.	Max.	
Quiescent Device Current, IDD Max.	-	0,5	5	0.25	0.25	7.5	7.5	-	0.01	0,25	μΑ
	-	0,10	10	0.5	0.5	15	15	-	0.01	0.5	
	-	0,15	15	1	1	30	30	-	0.01	1	
	-	0,20	20	5	5	150	150	_	0.02	5	
Output Low	0.4	0,5	5	0.64	0.61	0.42	0.36	0.51	1		. mA
(Sink) Current IOL Min.	0.5	0,10	10	1.6	1.5	11	0.9	13	2.6		
	1.5	0,15	15	4.2	4	2.8	2.4	34	6.8		
Output High	4.6	0,5	5	-0.64	-0.61	0.42	-0.36	~0.51	- 1		
(Source)	2.5	0,5	5	-2	-18	-1.3	-1 15	-16	-32		
Current, IOH Min.	9,5	0,10	10	-16	-1.5	-11	-0.9	-1.3	-26		
IOH MILLE	13.5	0,15	15	-4.2	- 4	-2.8	-2.4	-3.4	-68		
Output Voltage:	-	0,5	5	0.05				0	0.05	V	
Low Level, Vol. Max.	-	0,10	10	0.05				U	0 05		
VOL Max.		0,15	15	0.05				0	0.05		
Output Voltage: * High-Level, VOH Min.	- 1	0,5	5	4 95			4.95	5			
		0,10	10	9.95			9,95 1	10			
	-	0,15	15	14.95			14.95	15			
Input Low Voltage, VIL Max.	0.5,4.5		5	1.5 3				-	1.5	~	
	1,9	-	10				-	—	3		
	1.5,13.5	÷.,	. 15	4			-	-	4		
Input High Voltage, VIH Min.	0.5,4.5	-	5	3.5			3.5	-		v	
	1,9	-	10	7			1	-	-		
	1.5,13.5	-	15		1	1		11	-	—	
Input Current	1997 - A	0,18	18	± 0.1	± 0.1	±1	±1	-	±10 ⁻⁵	±01	μA





3

COMMERCIAL CMOS HIGH VOLTAGE ICs

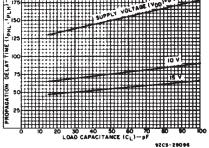


Fig. 7 — Typical propagation delay time as a function of load capacitance.

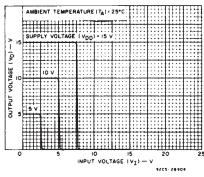
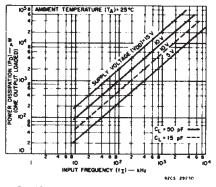
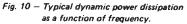


Fig. 9.— Typical voltage transfer characteristics (NOR output).

CD4078B Types





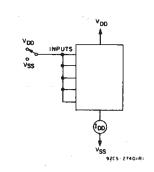


Fig. 11 — Quiescent-device-current test circuit.

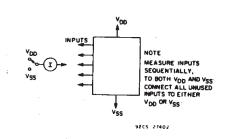
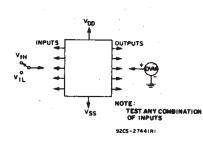
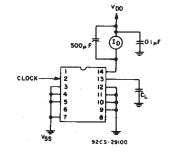


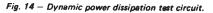
Fig. 12 - Input current test circuit.

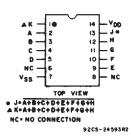


÷

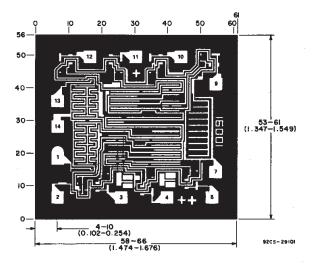
Fig. 13 - Input-voltage test circuit.











Dimensions and pad layout for CD4078BH.

Dimensions in parentheses are in millimeters and are derived from the basic inch dimensions as indicated. Grid graduations are in mils (10^{-3} inch) .

IMPORTANT NOTICE

Texas Instruments and its subsidiaries (TI) reserve the right to make changes to their products or to discontinue any product or service without notice, and advise customers to obtain the latest version of relevant information to verify, before placing orders, that information being relied on is current and complete. All products are sold subject to the terms and conditions of sale supplied at the time of order acknowledgement, including those pertaining to warranty, patent infringement, and limitation of liability.

TI warrants performance of its semiconductor products to the specifications applicable at the time of sale in accordance with TI's standard warranty. Testing and other quality control techniques are utilized to the extent TI deems necessary to support this warranty. Specific testing of all parameters of each device is not necessarily performed, except those mandated by government requirements.

CERTAIN APPLICATIONS USING SEMICONDUCTOR PRODUCTS MAY INVOLVE POTENTIAL RISKS OF DEATH, PERSONAL INJURY, OR SEVERE PROPERTY OR ENVIRONMENTAL DAMAGE ("CRITICAL APPLICATIONS"). TI SEMICONDUCTOR PRODUCTS ARE NOT DESIGNED, AUTHORIZED, OR WARRANTED TO BE SUITABLE FOR USE IN LIFE-SUPPORT DEVICES OR SYSTEMS OR OTHER CRITICAL APPLICATIONS. INCLUSION OF TI PRODUCTS IN SUCH APPLICATIONS IS UNDERSTOOD TO BE FULLY AT THE CUSTOMER'S RISK.

In order to minimize risks associated with the customer's applications, adequate design and operating safeguards must be provided by the customer to minimize inherent or procedural hazards.

TI assumes no liability for applications assistance or customer product design. TI does not warrant or represent that any license, either express or implied, is granted under any patent right, copyright, mask work right, or other intellectual property right of TI covering or relating to any combination, machine, or process in which such semiconductor products or services might be or are used. TI's publication of information regarding any third party's products or services does not constitute TI's approval, warranty or endorsement thereof.

Copyright © 1998, Texas Instruments Incorporated